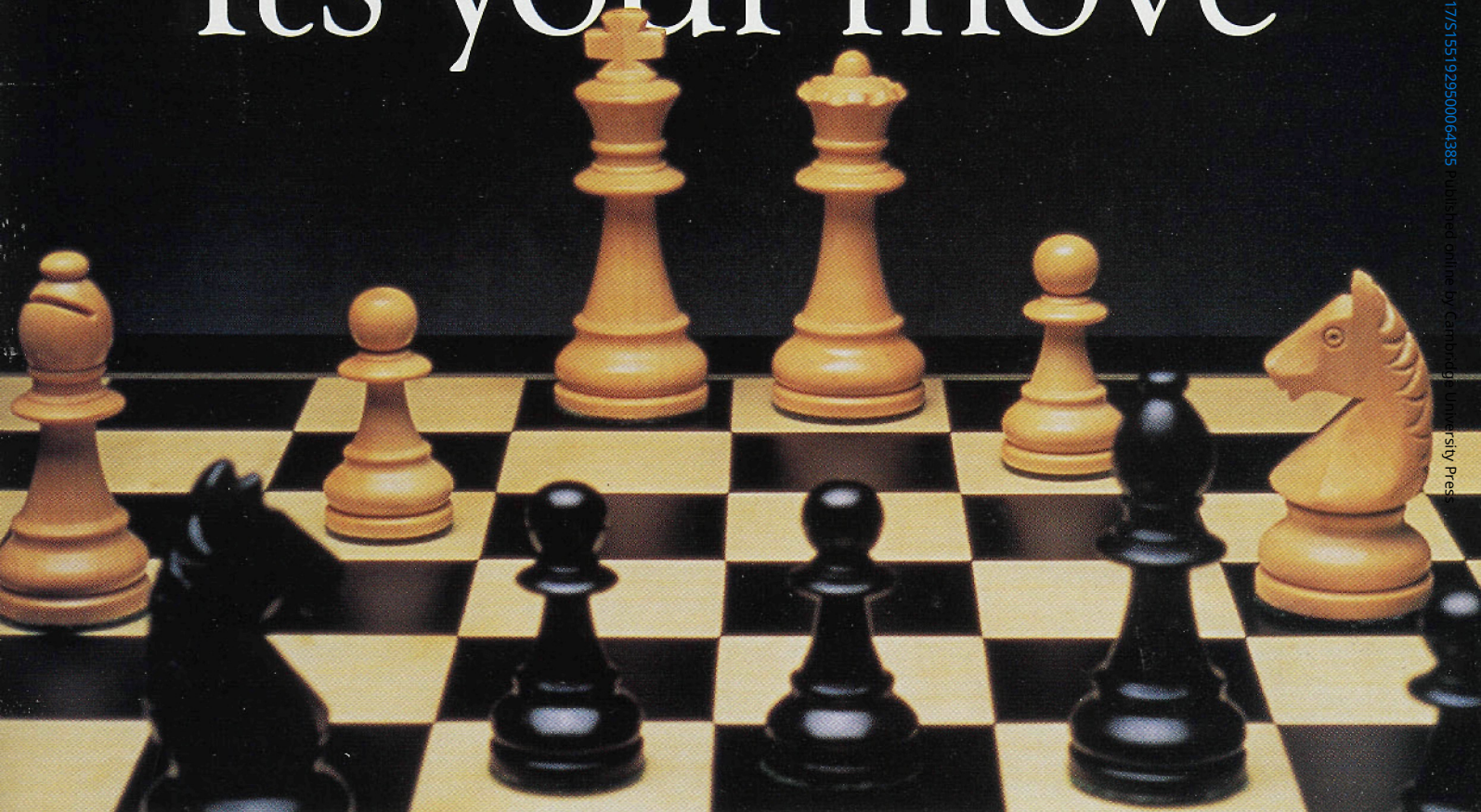


It's your move



ThermoMicroscopes offers more choices for nanoscale visualization than anyone. That means you choose the best scanning probe microscope for your application. Consider...

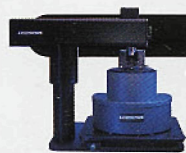
Explorer

The most versatile SPM ever built. Scans samples of any size. Dedicated system solutions for polymer and life sciences.



CP Research

The research SPM instrument of choice. Offers the most integrated scanning modes available in a single instrument.



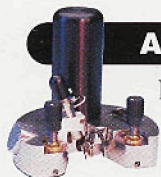
AutoProbe M5

An analytical instrument designed for industrial applications. Advanced SPM technology at an affordable price.



Aurora NSOM

Designed and built by the world's leading manufacturer of NSOM systems. Features patented tuning-fork technology.



THERMOMICROSCOPES
Park Scientific Instruments **TOPOMETRIX**

1171 Borregas Avenue, Sunnyvale, CA 94089
Telephone 408.747.1600 Fax 408.747.1601
info@thermomicromicro.com

And those are just our opening moves. We've got more. *Lot's more.* So consider your choices carefully. Then make your move to www.thermomicromicro.com.

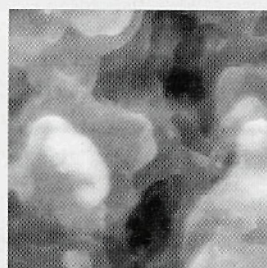
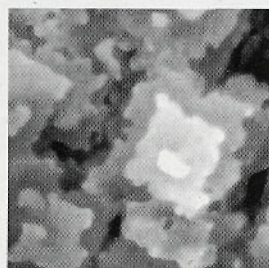
THE DIFFERENCE YOU CAN MEASURE

Circle Reader Inquiry #5

As Easy As It Looks



https://doi.org/10.1017/S1551929500064385 Published online by Cambridge University Press



PEO at 60°C with evidence of melting clearly shown after 2 minutes.

- ▶ **Based on a Simple PC Interface.**
- ▶ **Intuitive Operation with a Mouse Alone.**
- ▶ **Capable of Imaging Under Either Ambient or High Vacuum and at Both High and Low Temperatures.**
- ▶ **Fully Vibrationally Isolated.**
- ▶ **Capable of Wet or Dry Imaging.**
- ▶ **Variable Gas Pressure/Temperature.**

The new JSPM-4200 is a multipurpose turnkey Scanning Probe Microscope (SPM) capable of imaging using a myriad of different modes and

NEW - Multi-Environmental

SPM

Scanning Probe Microscope

accessories. Imaging modes include STM, STS (Scanning Tunneling Spectroscopy), CITS (Current Imaging Tunneling Microscopy), AFM, LFM (Lateral Force Microscopy), Non-contact Mode AFM, Discrete Contact Mode AFM, Lateral Modulation LFM, MFM (Magnetic Force Microscopy), and Force Modulation Microscopy.

If you would like to learn more about JEOL SPM's please give us a call and arrange for your own hands-on demonstration so that we can prove to you that it really is "As Easy As It looks".

JEOL USA, Inc., 11 Dearborn Road, Peabody, MA 01960
Tel: 978/535-5900 • Fax: 978/536-2205
Email: spm@jeol.com • WEB: <http://www.jeol.com>

JEOL

Circle Reader Inquiry #3